

EN27C010 1Megabit EPROM (128K x 8)

FEATURES

- Fast Read Access Time:
 -45, -55, -70, and -90ns
- Single 5V Power Supply
- Programming Voltage +12.75V
- QuikRite[™] Programming Algorithm
- Typical programming time 20µs
- Low Power CMOS Operation
- 1µA Standby (Typical)
- 30mA Operation (Max.)
- CMOS- and TTL-Compatible I/O
- High-Reliability CMOS Technology

- Latch-Up Immunity to 100mA from -1V to V_{CC} + 1V
- Two-Line Control ($\overline{OE} \& \overline{CE}$)
- Standard Product Identification Code
- JEDEC Standard Pinout
 - 32-pin PDIP
 - 32-pin PLCC
 - 32-pin TSOP (Type 1)
- Commercial and Industrial Temperature Ranges

GENERAL DESCRIPTION

The EN27C010 is a low-power 1-Megabit, 5V-only one-time-programmable (OTP) read-only memory (EPROM). Organized into 128K words with 8 bits per word, it features QuikRite[™] single-address location programming, typically at 20µs per byte. Any byte can be accessed in less than 45ns, eliminating the need for WAIT states in high-performance microprocessor systems. The EN27C010 has separate Output Enable (OE) and Chip Enable (CE) controls which eliminate bus contention issues.

FIGURE 1. PDIP

Pin Name	Function
A0-A16	Addresses
DQ0-DQ7	Outputs
CE	Chip Enable
OE	Output Enable
PGM	Program Strobe
NC	No Connect

PDIP Top View

VPP	1 ●	\bigcirc	32	□ vcc
A16 🗆	2		31	D PGM
A15 🗆	3		30	□ NC
A12 🗆	4		29	🗌 A14
A7 🗆	5		28	🗌 A13
A6 🗆	6		27	🗆 A8
A5 🗆	7		26	🗌 A9
A4 🗆	8		25	□ <u>A11</u>
A3 🗆	9		24	OE
A2 🗆	10		23	<u> </u>
A1 🗆	11		22	
A0 🗆	12		21	DQ7
DQ0	13		20	DQ6
DQ1 🗌	14		19	DQ5
DQ2	15		18	DQ4
vss 🗆	16		17	DQ3
				l



FIGURE 2. TSOP

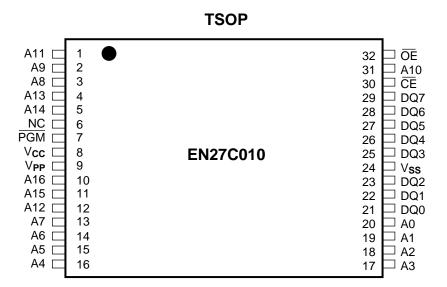
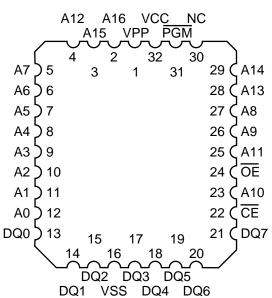


FIGURE 3. PLCC

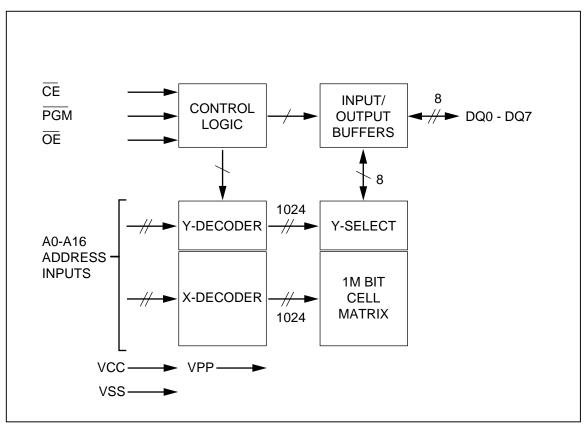


PLCC Top View

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FIGURE 4. BLOCK DIAGRAM



FUNCTIONAL DESCRIPTION

THE QUIKRITE[™] PROGRAMMING OF THE EN27C010

When the EN27C010 is delivered, the chip has all 1M bits in the "ONE", or HIGH state. "ZEROs" are loaded into the EN27C010 through the procedure of programming.

The programming mode is entered when 12.75 \pm 0.25V is applied to the V_{PP} pin, \overline{OE} is at V_{IH}, and CE and PGM are at V_{IL}. For programming, the data to be programmed is applied with 8 bits in parallel to the data pins.

The QUIKRITETM programming flowchart in Figure 5 shows Eon's interactive programming algorithm. The interactive algorithm reduces programming time by using 20 μ s to 100 μ s programming pulses and giving each address only as many pulses as is necessary in order to reliably program the data. After each pulse is applied to a given address, the data in that address is verified. If the data is not verified, additional pulses are given until it is verified or until the maximum number of pulses is reached. This process is repeated while sequencing through each address of the EN27C010. This part of the programming algorithm is done at V_{CC} = 6.25V to assure that each EPROM bit is programmed to a sufficiently high threshold voltage. This ensures that all bits have sufficient margin. After the final address is completed, the entire EPROM memory is read at V_{CC} = V_{PP} = 5.25 ± 0.25V to verify the entire memory.



PROGRAM INHIBIT MODE

Programming of multiple EN27C010 in parallel with different data is also easily accomplished by using the Program Inhibit Mode. Except for \overrightarrow{CE} , all like inputs of the parallel EN27C010 may be common. A TTL low-level program pulse applied to an EN27C010 \overrightarrow{CE} input with $\underline{V_{PP}} = 12.75 \pm 0.25V$, PGM LOW, and \overrightarrow{OE} HIGH will program that EN27C010. A high-level CE input inhibits the other EN27C010 from being programmed.

PROGRAM VERIFY MODE

Verification should be performed on the programmed bits to determining that they were correctly programmed. The verification should be performed with \overrightarrow{OE} and \overrightarrow{CE} at V_{IL}, \overrightarrow{PGM} at V_{IH}, and V_{PP} at it programming voltage.

AUTO PRODUCT IDENTIFICATION

The Auto Product Identification mode allows the reading out of a binary code from an EPROM that will identify its manufacturer and type. This mode is intended for use by programming equipment for the purpose of automatically matching the device to be programmed with its corresponding programming algorithm. This mode is functional in the $25^{\circ}C \pm 5^{\circ}C$ ambient temperature range that is required when programming the EN27C010.

To activate this mode, the programming equipment must force 12.0 V \pm 0.5V on address line A9 of the EN27C010. Two identifier bytes may then be sequenced from the device outputs by toggling address line A0 from V_{IL} to V_{IH}, when A1 = V_{IH}. All other address lines must be held at V_{IL} during Auto Product Identification mode.

Byte 0 (A0 = V_{IL}) represents the manufacturer code, and byte 1 (A0 = V_{IH}), the device code. For the EN27C010, these two identifiers bytes are given in the Mode Select Table. All identifiers for manufacturer and device codes will possess odd parity, with the MSB (DQ7) defined as the parity bit. When A1 = V_{IL} , the EN27C010 will read out the binary code of 7F, continuation code, to signify the unavailability of manufacturer ID codes.



READ MODE

The EN27C010 has two control functions, both of which must be logically satisfied in order to obtain data at the outputs. Chip Enable (CE) is the power control and should be used for device selection. Output Enable (OE) is the output control and should be used to gate data to the output pins, independent of device selection. Assuming that addresses are stable, address access time (t_{ACC}) is equal to the delay from CE to output (t_{CE}). Data is available at the outputs (t_{OE}) after the falling edge of OE, assuming the CE has been LOW and addresses have been stable for at least t_{ACC} - t_{OE} .

STANDBY MODE

The EN27C010 has CMOS standby mode which reduces the maximum V_{CC} current to 20µA. It is placed in CMOS standby when \overline{CE} is at V_{CC} ± 0.3 V. The EN27C010 also has a TTL-standby mode which reduces the maximum V_{CC} current to 1.0 mA. It is placed in TTL-standby when \overline{CE} is at V_{IH}. When in standby mode, the outputs are in a high-impedance state, independent of the OE input.

TWO-LINE OUTPUT CONTROL FUNCTION

To accommodate multiple memory connections, a two-line control function is provided to allow for:

- 1. Low memory power dissipation,
- 2. Assurance that output bus contention will not occur.

It is recommended that \overline{CE} be decoded and used as the primary device-selection function, while \overline{OE} be made a common connection to all devices in the array and connected to the READ line from the system control bus. This assures that all deselected memory devices are in their low-power standby mode and that the output pins are only active when data is desired from a particular memory device.

SYSTEM CONSIDERATIONS

During the switch between active and standby conditions, transient current peaks are produced on the rising and falling edges of Chip Enable. The magnitude of these transient current peaks is dependent on the output capacitance loading of the device. At a minimum, a 0.1μ F ceramic capacitor (high frequency, low inherent inductance) should be used on each device between VCC and VSS to minimize transient effects. In addition, to overcome the voltage drop caused by the inductive effects of the printed circuit board traces on EPROM arrays, a 4.7μ F bulk electrolytic capacitor should be used between VCC and VSS for each eight devices. The location of the capacitor should be close to where the power supply is connected to the array.



MODE SELECT TABLE

Mode	CE	OE	PGM	A0	A1	A9	V _{PP}	Output
Read	V _{IL}	VIL	X ⁽²⁾	Х	Х	Х	V _{CC}	D _{OUT}
Output Disable	V _{IL}	VIH	Х	Х	Х	Х	V _{CC}	High Z
Standby (TTL)	V _{IH}	Х	Х	Х	Х	Х	V _{CC}	High Z
Standby (CMOS)	$V_{CC}\pm0.3V$	Х	Х	Х	Х	Х	V _{CC}	High Z
Program ⁽⁴⁾	V _{IL}	V _{IH}	VIL	Х	Х	Х	V _{PP}	D _{IN}
Program Verify	V _{IL}	VIL	V _{IH}	Х	Х	Х	V _{PP}	D _{OUT}
Program Inhibit	V _{IH}	Х	Х	Х	Х	Х	V _{PP}	High Z
Manufacturer Code (3)	V _{IL}	V _{IL}	Х	VIL	V _{IH}	VH ⁽¹⁾	V _{CC}	1C
Device Code ⁽³⁾	V _{IL}	V _{IL}	Х	V _{IH}	V _{IH}	VH ⁽¹⁾	V _{CC}	01

NOTES:

 $\begin{array}{ll} 1) & VH = 12.0V \pm 0.5V \\ 2) & X = Either \, V_{IH} \, or \, V_{IL} \end{array}$

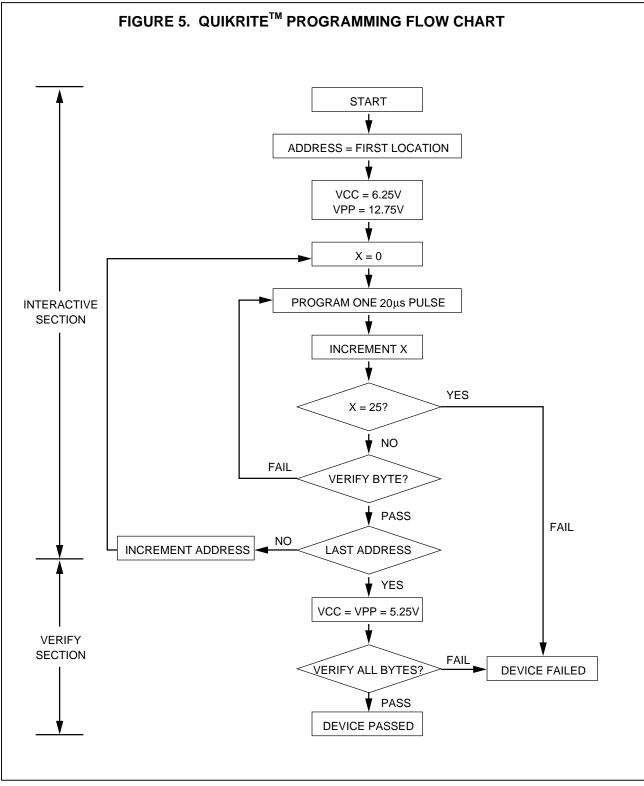
3) For Manufacturer Code and Device Code, $A1 = V_{IH}$ When $A1 = V_{IL}$, both codes will read 7F

4) See DC Programming Characteristics for V_{PP} voltage during programming

EON'S STANDARD PRODUCT IDENTIFICATION CODE

		Pins								Hex Data	
Code	A0	A1	DQ7	DQ6	DQ5	DQ4	DQ3	DQ2	DQ1	DQ0	
Manufacturer	0	1	0	0	0	1	1	1	0	0	1C
Device Type	1	1	0	0	0	0	0	0	0	1	01
Continuation	0	0	0	1	1	1	1	1	1	1	7F
	1	0	0	1	1	1	1	1	1	1	7F





NOTE 1: Either 100µs or 20µs pulse.



ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-65 °C to +125 °C
Ambient Temperature with Power Applied	-40 ° C to +85 ° C
Voltage with Respect to V _{ss} All pins except A9, V _{PP} , V _{CC} A9, V _{PP} V _{CC}	-0.6V to V _{CC} + 0.5V -0.6V to +13.5V -0.6V to +7.0V

OPERATING RANGES

Commercial (C) Case Temperature(Tc)	0 ° C to +70 ° C
Industrial (I) Case Temperature(Tc)	-40 ° C to +85 ° C
Supply READ Voltages	+4.50V to +5.5V

(Functionality is guaranteed between these limits)

Stresses above those shown above may cause permanent damage to the device. This is a stress rating only and operation above these specifications for extended periods may affect device reliability. Operation outside the "OPERATING RANGES" shown above voids any and all warranty provisions.

DC CHARACTERISTICS FOR READ OPERATION

Symbol	Parameter	Min.	Max.	Unit	Conditions
V _{OH}	Output High Voltage	2.4		V	I _{OH} = -0.4mA
V _{OL}	Output Low Voltage		0.45	V	$I_{OL} = 2.1 \text{mA}$
V _{IH}	Input High Voltage	2.0	V _{CC} +0.5	V	
V _{IL}	Input Low Voltage	-0.3	0.8	V	
ILI	Input Leakage Current	-5	5	μΑ	$V_{IN} = 0$ to 5.5V
I _{LO}	Output Leakage Current	-10	10	μA	$V_{OUT} = 0$ to 5.5V
I _{CC3}	V _{CC} Power -Down Current		10	μΑ	$\overline{\text{CE}} = V_{\text{CC}} \pm 0.3 \text{V}$
I _{CC2}	V _{CC} Standby Current		1.0	mA	$\overline{CE} = V_{IH}$
I _{CC1}	V _{CC} Active Current		30	mA	$\overline{CE} = V_{IL}$, f=5MHz,
					I _{OUT} = 0mA
I _{PP}	V _{PP} Supply Current Read		100	μA	$\overline{CE} = \overline{OE} = V_{IL}$,
					V _{PP} = 5.5V

CAPACITANCE

Symbol	Parameter	Тур.	Max.	Unit	Conditions
CIN	Input Capacitance	8	12	pF	$V_{IN} = 0V$
COUT	Output Capacitance	8	12	pF	$V_{OUT} = 0V$
CVPP	V _{PP} Capacitance	18	25	pF	$V_{PP} = 0V$

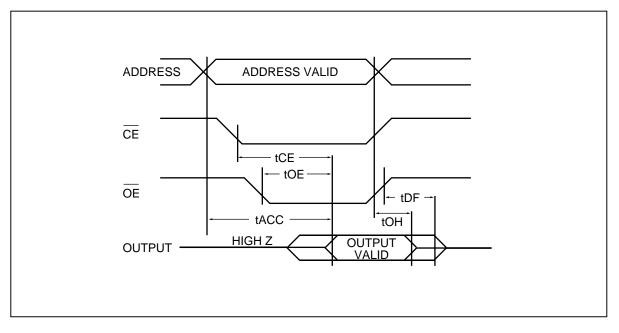


AC CHARACTERISTICS FOR READ OPERATION

			EN27C010 / EN27C010L								
			-4	5	-55		-70		-90		
Symbol	Parameter	Condition	Min	Max	Min	Max	Min	Max	Min	Max	Unit
tACC (3)	Address to Output Delay	$\overline{CE} = \overline{OE} = V_{IL}$		45		55		70		90	ns
tCE (2)	CE to Output Delay	OE = V _{IL}		45		55		70		90	ns
tOE (2, 3)	OE to Output Delay	$\overline{OE} = V_{IL}$		25		25		30		35	ns
tDF (4, 5)	OE or CE High whichever occur	•		20		20		25		25	ns
tOH	Out <u>pu</u> t Hold from or OE , whichev		0		0		0		0		ns

Note: Please contact Marketing Department for other speed requirements.

FIGURE 6. AC WAVEFORMS FOR READ OPERATION





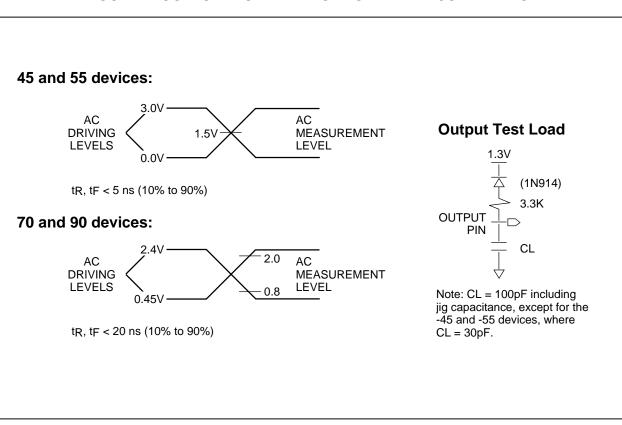


FIGURE 7. OUTPUT TEST WAVEFORMS AND MEASUREMENTS

DC PROGRAMMING CHARACTERISTICS

		Test	L		
Symbol	Parameter	Conditions	Min.	Max	Units
Ι _{LI}	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		5.0	μΑ
VIL	Input Low Level		-0.5	0.8	V
VIH	Input High Level		$0.7 V_{CC}$	V _{CC} + 0.5	V
V _{OL}	Output Low Voltage	I _{OL =} 2.1 mA		0.45	V
V _{OH}	Output High Voltage	I _{OH =} -400 μA	2.4		V
I _{CC2}	V _{CC} Supply Current			40	mA
I _{PP2}	V _{PP} Supply Current	$\overline{CE} = \overline{PGM} = V_{IL}$		10	mA
V _{ID}	A9 Product Identification Voltage		11.5	12.5	V





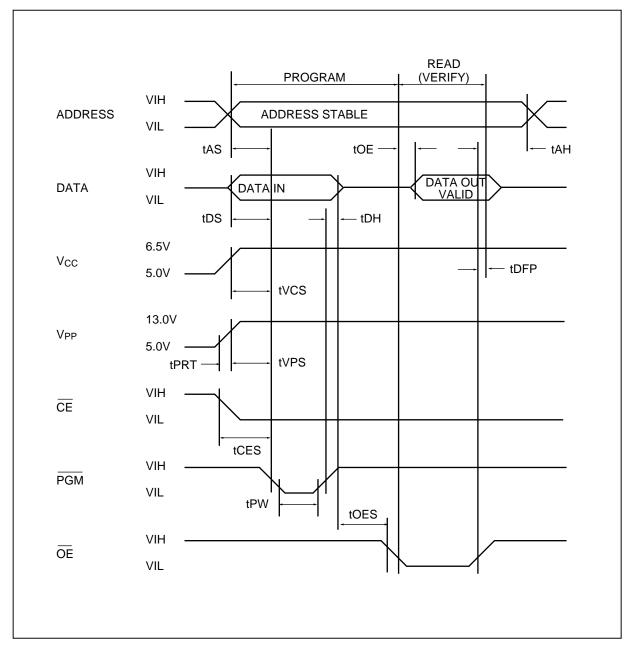


FIGURE 8. PROGRAMMING WAVEFORMS

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SWITCHING PROGRAMMING CHARACTERISTICS

 $(T_A = +25 \circ C \pm 5 \circ C)$

PARAMETER SYMBOL				
STANDARD	PARAMETER DESCRIPTION	Min.	Max	Units
t _{AS}	Address Setup Time	2		μs
t _{OES}	OE Setup Time	2		μs
t _{DS}	Data Setup Time	2		μs
t _{AH}	Address Hold Time	0		μs
t _{DH}	Data Hold Time	2		μs
t _{DFP}	Output Enable to Output Float Delay	0	130	ns
t _{VPS}	V _{PP} Setup Time	2		μs
t _{PW}	PGM Program Pulse Width	20	105	μs
t _{VCS}	V _{cc} Setup Time	2		μs
t _{CES}	CE Setup Time	2		μs
t _{OE}	Data Valid from OE		150	ns

ORDERING INFORMATION

